

Supporting Information

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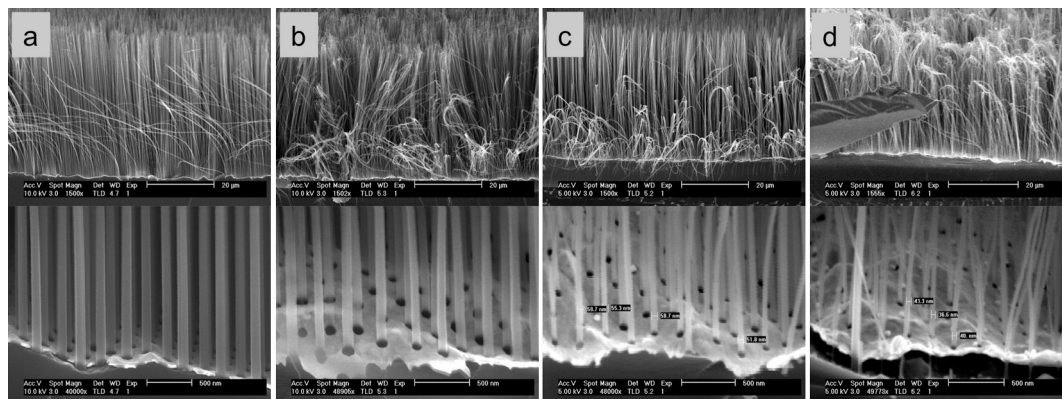


Fig. S1. MACE processing with Au catalyst mask. The increase in the colloidal etch time (from A to D) dictates the results in

- decrease of the catalytic hole mask size
- decrease in the diameter of the Si-nanowires. Three direct benefits follow:
 - (i) lower gravimetric electrode loading,
 - (ii) higher polymer/electrolyte uptake,
 - (iii) easier volume expansion/mechanical stress accommodation during the lithiation/delithiation of Si-nanowires. Nanowires as small as 20 nm in diameter have been fabricated using this method.

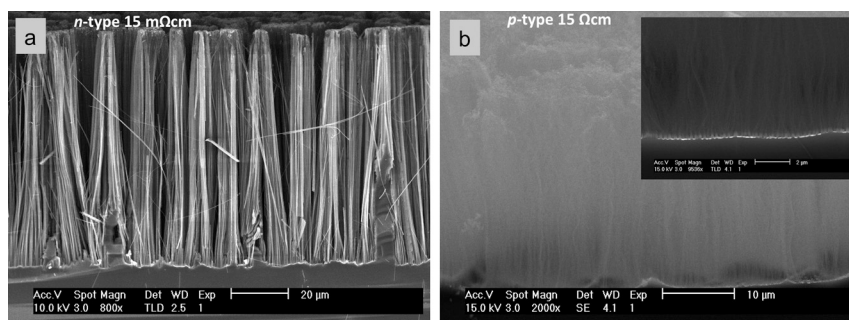


Fig. S2. MACE processing with Pt catalyst mask. (A) Ultra-high aspect ratio Si-nanowires (*n*-type Si, 15 mΩcm) fabricated using a Pt (25 nm thick) mask and 4.8M HF + 0.2M H₂O₂ as etchant solution. The etching time was 60 min resulting in a etch rate of more than 1 μm/min. (B) Applying the same recipe on *p*-type 15 Ωcm silicon produced highly porous and brittle nanowires.

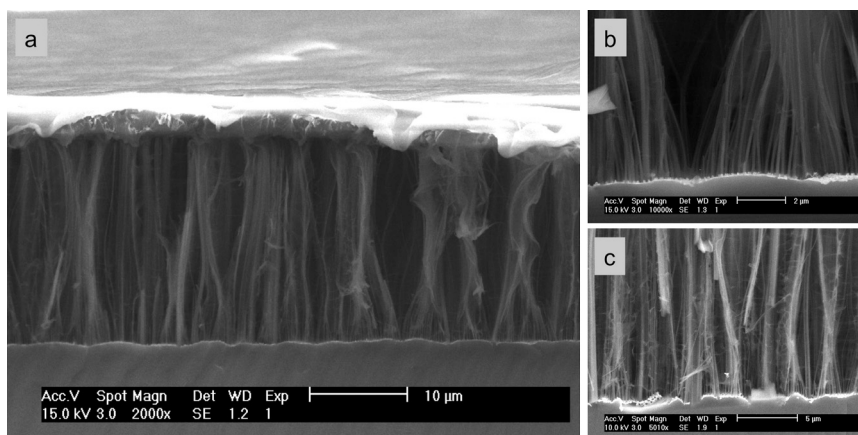


Fig. S3. Polymer infiltration. (A) The polymer infiltration was performed with a 5% polymer by wt. solution in acetone. Conformal coating of the Si nanowires failed when simply adding and drying an excess polymer solution. A continuous polymer film formed on top of the substrate without infiltrating the nanowires presumably due to a fast evaporation rate of the solvent within the high surface area Si nanowire forest. (B, C) Enlarged views evidencing the poor quality of the polymer infiltrated Si-nanowire array.

